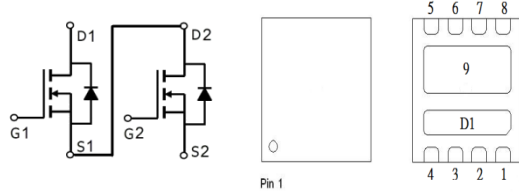




**PRODUCT SUMMARY**

	$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
Q2	30V	7mΩ	39A
Q1	30V	10.5mΩ	31A



1 : G1  
2,3,4 : D1  
5,6,7 : S2  
8 : G2  
9 : S1/D2

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25\text{ °C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	Q2	Q1	UNITS
Drain-Source Voltage		$V_{DS}$	30	30	V
Gate-Source Voltage		$V_{GS}$	±20	±20	V
Continuous Drain Current <sup>3</sup>	$T_C = 25\text{ °C}$	$I_D$	39	31	A
	$T_C = 100\text{ °C}$		25	20	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	50	45	
Continuous Drain Current <sup>3</sup>	$T_A = 25\text{ °C}$	$I_D$	12	9.5	
	$T_A = 70\text{ °C}$		10	7.6	
Avalanche Current		$I_{AS}$	23	17.5	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	26.4	15.3	mJ
Power Dissipation	$T_C = 25\text{ °C}$	$P_D$	20	19	W
	$T_C = 100\text{ °C}$		8.3	7.6	
Power Dissipation	$T_A = 25\text{ °C}$	$P_D$	2.2	1.7	W
	$T_A = 70\text{ °C}$		1.4	1.1	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL		TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$	Q2		56	°C / W
	$R_{\theta JA}$	Q1		72	
Junction-to-Case	$R_{\theta JC}$	Q2		6	
	$R_{\theta JC}$	Q1		6.5	

<sup>1</sup>Pulse width limited by maximum junction temperature  $T_{J(MAX)}=150\text{ °C}$ .

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25\text{ °C}$ . The value in any given application depends on the user's specific board design.

<sup>3</sup>Package limitation current is Q2=19A , Q1=11A.

**ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	Q2	30		V
			Q1	30		
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	Q2	1.3	1.75	2.3
			Q1	1.3	1.75	2.3
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	Q2			±100
			Q1			±100
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	Q2			1
			Q1			1
		V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 55 °C	Q2			10
			Q1			10
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 10A	Q2		6.7	9.5
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 9A	Q1		10.2	15.5
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A	Q2		5	7
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 9.5A	Q1		7.5	10.5
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 10A	Q2		66	
		V <sub>DS</sub> = 5V, I <sub>D</sub> = 9.5A	Q1		50	
<b>DYNAMIC</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz	Q2		961	
			Q1		627	
Output Capacitance	C <sub>oss</sub>		Q2		185	
			Q1		129	
Reverse Transfer Capacitance	C <sub>rss</sub>		Q2		121	
			Q1		97	
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	V <sub>GS</sub> = 10V	Q2	15.4	19.3	23.2
			Q1	11.2	14	16.8
		V <sub>GS</sub> = 4.5V	Q2	7.8	11.2	14.6
			Q1	5.5	7.8	10.1
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>	Q1 V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 9.5A	Q2		2.1	
			Q1		1.6	
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>	Q2		5.9		
		Q1		4.1		

Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	<p style="text-align: center;">Q2 <math>V_{DS} = 15V</math>, <math>I_D \cong 10A, V_{GS} = 10V, R_{GEN} = 6\Omega</math></p> <p style="text-align: center;">Q1 <math>V_{DS} = 15V</math>, <math>I_D \cong 9.5A, V_{GS} = 10V, R_{GEN} = 6\Omega</math></p>	Q2		13		nS
			Q1		12		
Rise Time <sup>2</sup>	$t_r$		Q2		57		
			Q1		48		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		Q2		35		
			Q1		27		
Fall Time <sup>2</sup>	$t_f$	Q2		70			
		Q1		39			

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25\text{ }^\circ\text{C}$ )**

Continuous Current <sup>3</sup>	$I_S$		Q2			16	A
			Q1			17	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 10A, V_{GS} = 0V$	Q2			1.2	V
		$I_F = 9.5A, V_{GS} = 0V$	Q1			1.1	
Reverse Recovery Time	$t_{rr}$	<p style="text-align: center;">Q2 <math>I_F = 10A, di_F/dt = 100A / \mu S</math></p> <p style="text-align: center;">Q1</p>	Q2		12		nS
			Q1		10.5		
Reverse Recovery Charge	$Q_{rr}$	$I_F = 9.5A, di_F/dt = 100A / \mu S$	Q2		3		nC
			Q1		3		

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

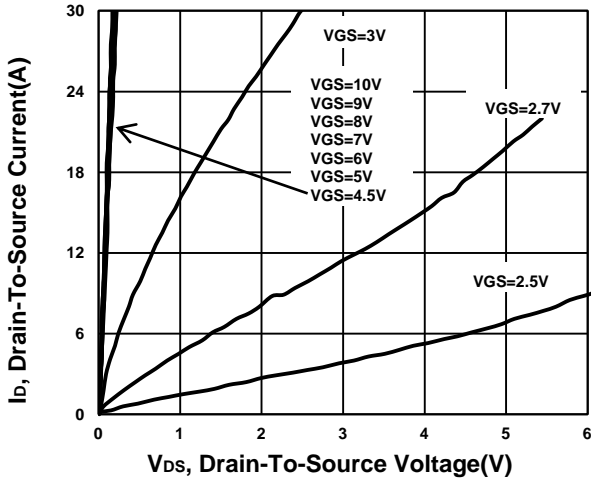
<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Package limitation current is Q2=19A , Q1=11A.

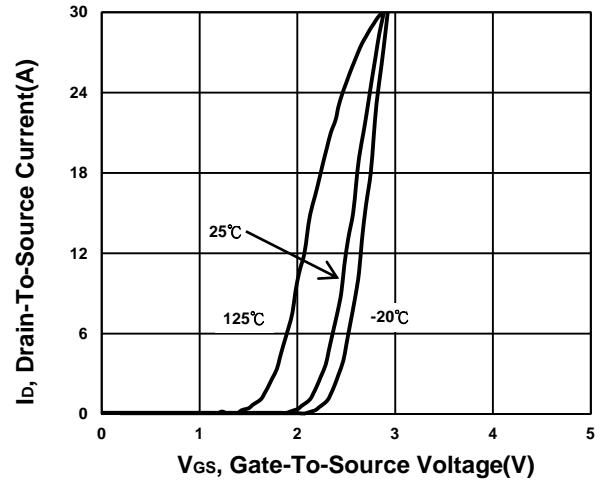
**TYPICAL PERFORMANCE CHARACTERISTICS**

**Q2**

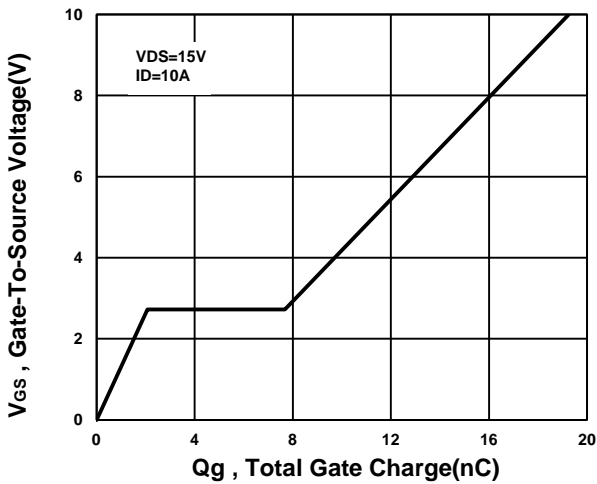
**Output Characteristics**



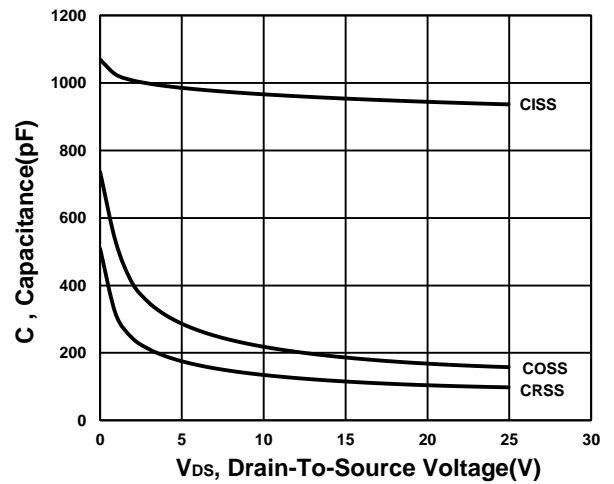
**Transfer Characteristics**



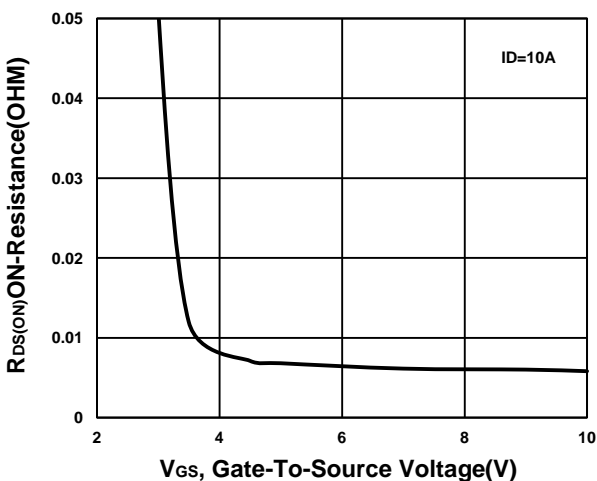
**Gate charge Characteristics**



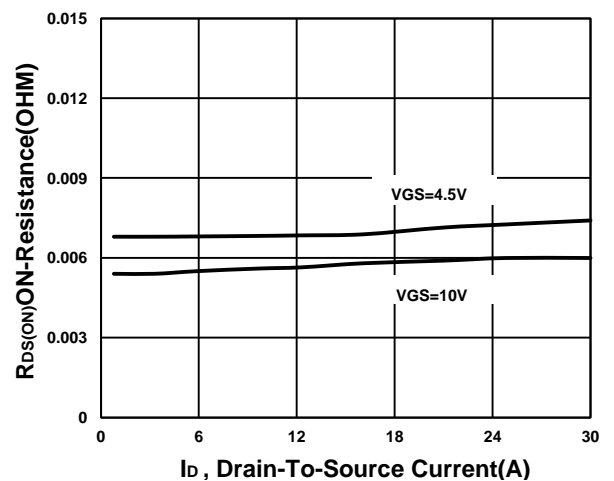
**Capacitance Characteristic**



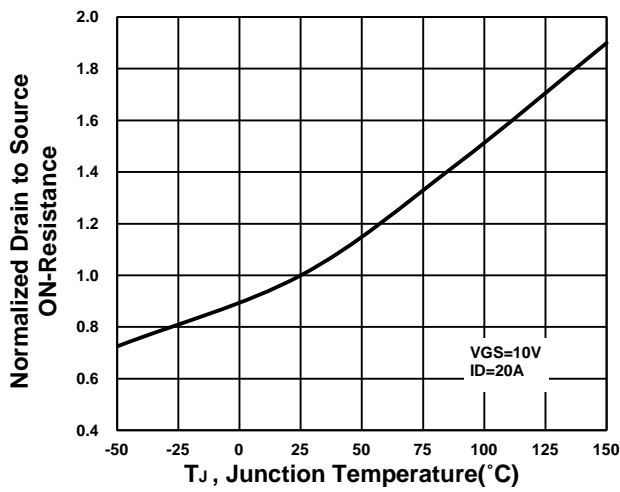
**On-Resistance VS Gate-To-Source**



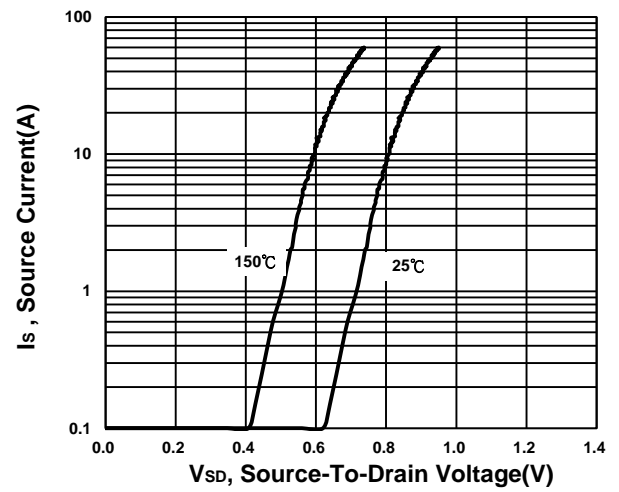
**On-Resistance VS Drain Current**



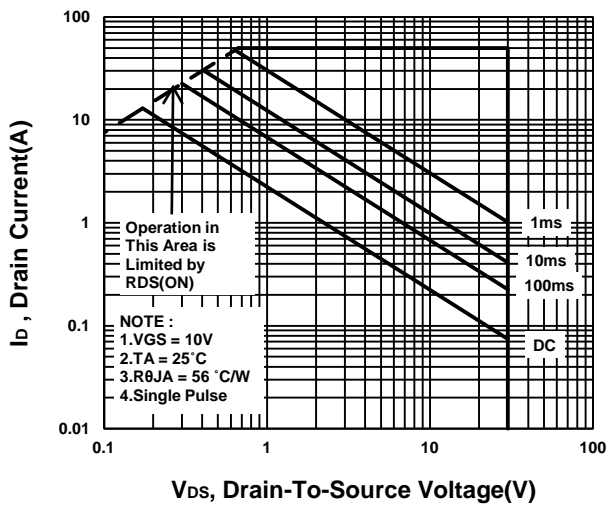
**On-Resistance VS Temperature**



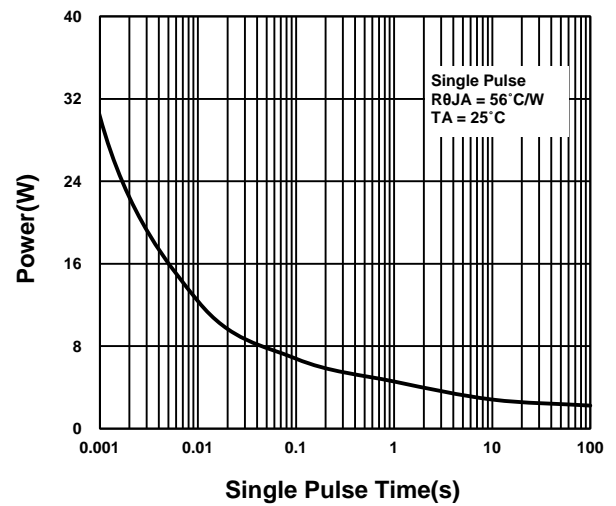
**Source-Drain Diode Forward Voltage**



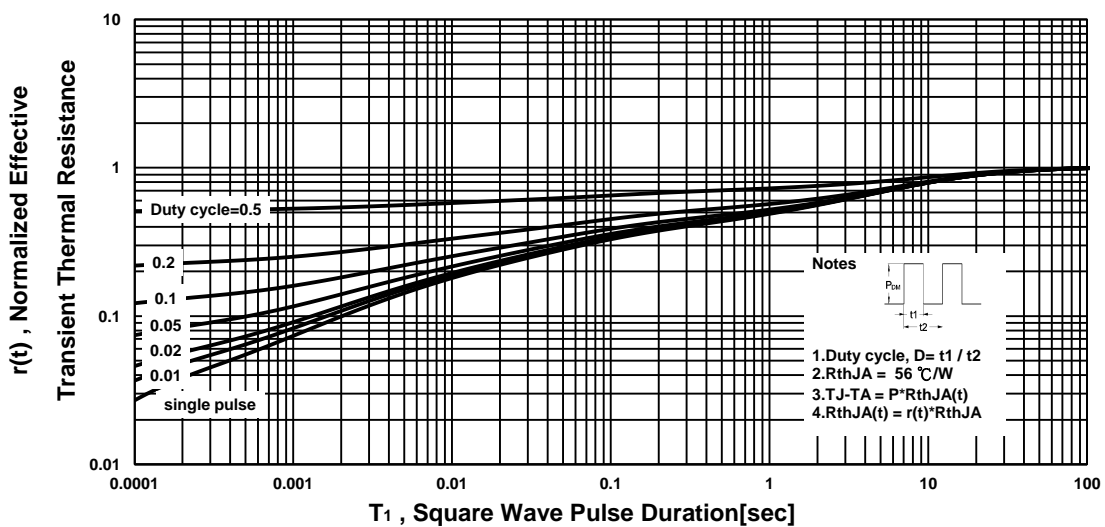
**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**

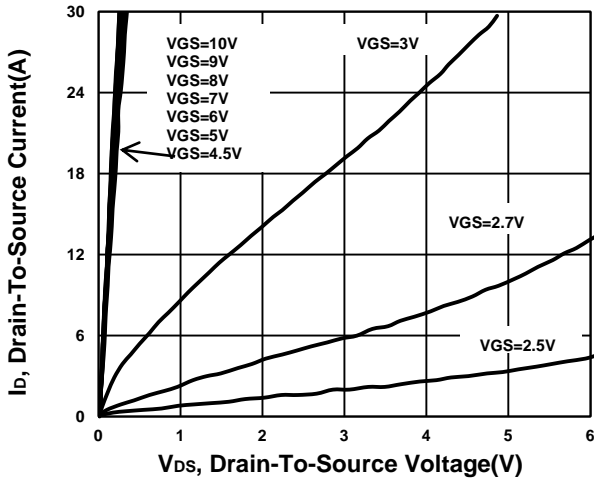


**Transient Thermal Response Curve**

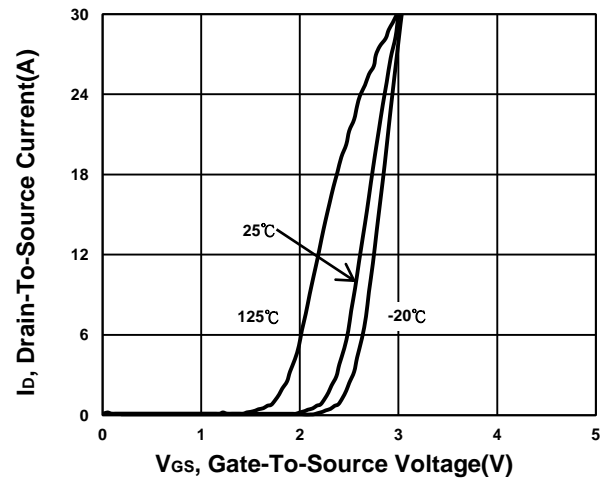


**Q1**

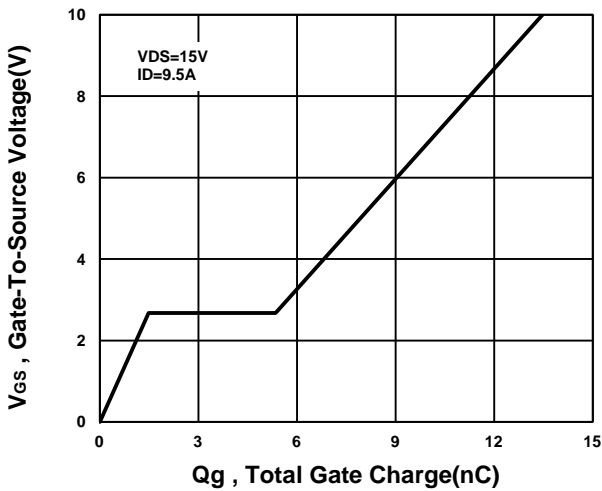
**Output Characteristics**



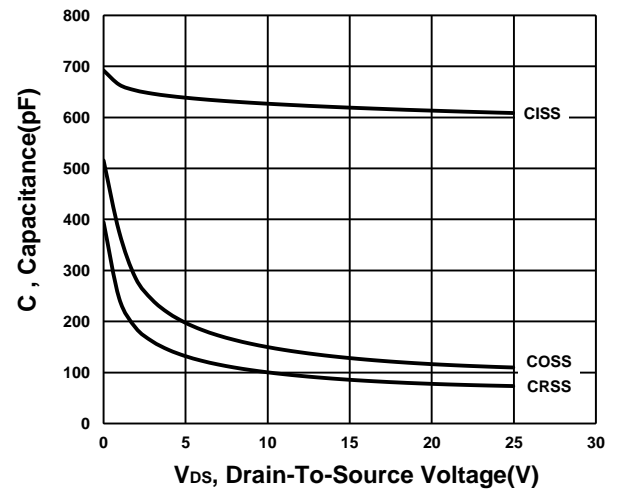
**Transfer Characteristics**



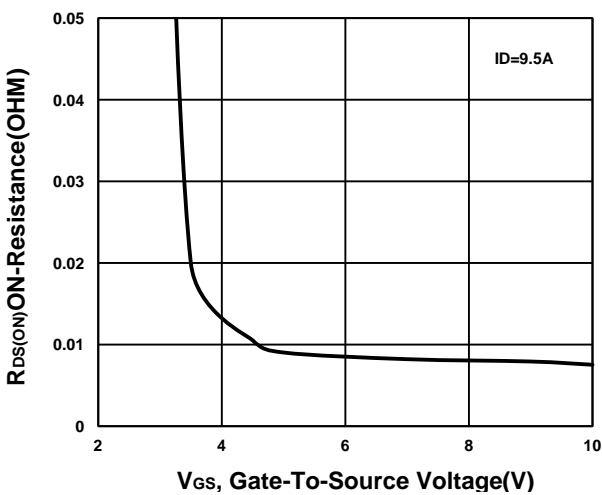
**Gate charge Characteristics**



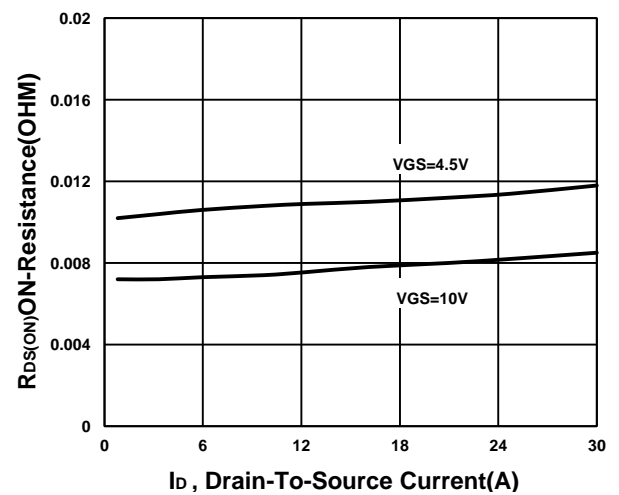
**Capacitance Characteristic**



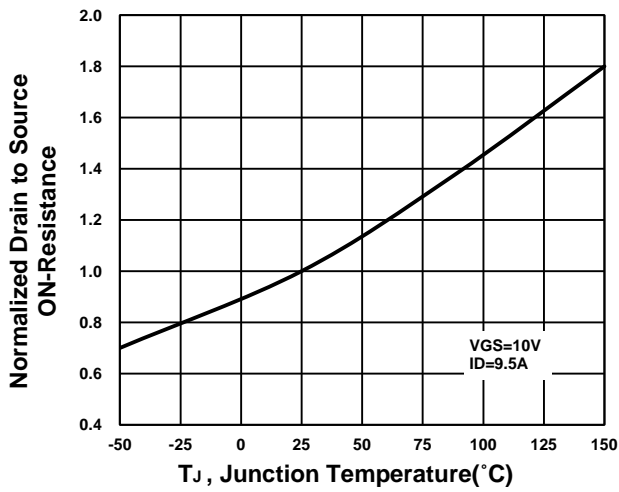
**On-Resistance VS Gate-To-Source**



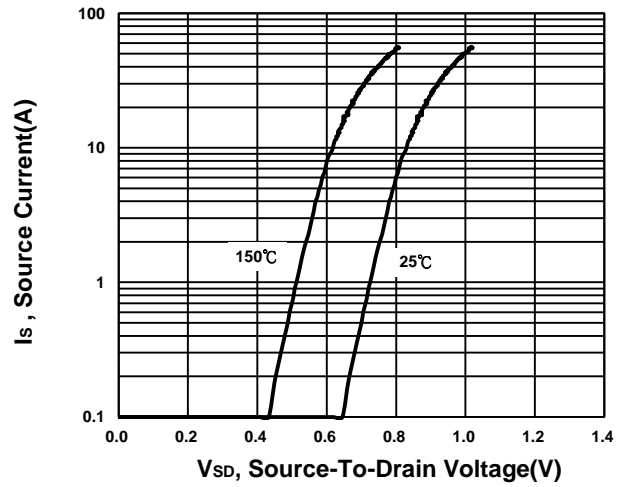
**On-Resistance VS Drain Current**



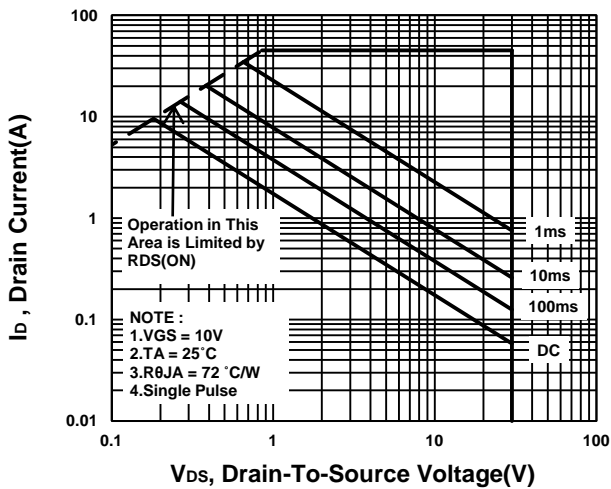
**On-Resistance VS Temperature**



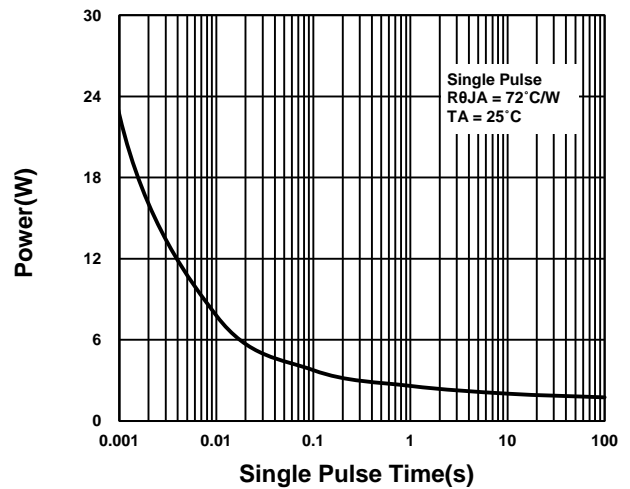
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

